TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TC74HC03AP, TC74HC03AF, TC74HC03AFN

# QUAD 2-INPUT NAND GATE (OPEN DRAIN)

The TC74HC03A is a high speed CMOS 2-INPUT NAND GATE fabricated with silicon gate C2MOS technology.

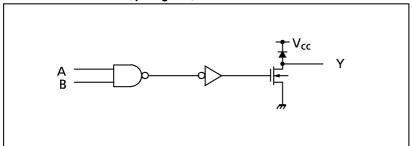
It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation. Pin configuration and function are the same as the TC74HC00A. But the TC74HC03A has, as its outputs, high performance MOS N-channel transistors. (OPEN-DRAIN outputs)This device can, thefore, with a suitable pull-up resistors, be used in wired-AND, LED driver and other application.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

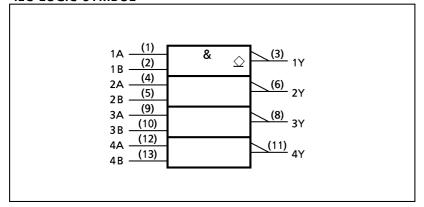
#### **FEATURES:**

- High Speed-----t<sub>pz</sub> = 5ns(typ.) at  $V_{CC} = 5V$
- Low Power Dissipation ·············· $I_{CC} = 1 \mu A(Max.)$  at  $Ta = 25 ^{\circ}C$
- High Noise Immunity  $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (Min.)
- Output Drive Capability ..... 10 LSTTL Loads
- Wide Operating Voltage Range ···· V<sub>CC</sub> (opr.) = 2V~6V
- Open Drain Structure
- Pin and Function Compatible with 74LS03

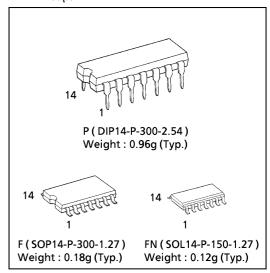
### SYSTEM DIAGRAM (per gate)



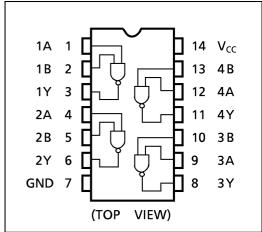
## **IEC LOGIC SYMBOL**



(Note) The JEDEC SOP (FN) is not available in Japan.



#### **PIN ASSIGNMENT**



#### TRUTH TABLE

Α	В	Υ
L	Г	Z
L	Н	Z
Н	L	Z
Н	Н	L

Z : High Impedance

## **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V <sub>CC</sub>	<b>−</b> 0.5~7	V
DC Input Voltage	V <sub>IN</sub>	$-0.5 \sim V_{CC} + 0.5$	V
DC Output Voltage	V <sub>OUT</sub>	−0.5~V <sub>CC</sub> + 0.5	V
Input Diode Current	I <sub>LK</sub>	± 20	mA
Output Diode Current	I <sub>OK</sub>	± 20	mA
DC Output Current	I <sub>OUT</sub>	+ 25	mA
DC V <sub>CC</sub> / Ground Current	I <sub>cc</sub>	± 50	mA
Power Dissipation	P <sub>D</sub>	500 (DIP)* / 180 (SOP)	mW
Storage Temperature	T <sub>stg</sub>	<b>−65~150</b>	°C

\*500mW in the range of Ta=  $-40^{\circ}\text{C}\sim65^{\circ}\text{C}$ . From Ta=65°C to 85°C a derating factor of  $-10\text{mW}/^{\circ}\text{C}$  shall be applied until 300mW.

#### **RECOMMENDED OPERATING CONDITIONS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	V <sub>cc</sub>	2~6	<b>\</b>
Input Voltage	V <sub>IN</sub>	0~V <sub>CC</sub>	<
Output Voltage	V <sub>OUT</sub>	0∼V <sub>cc</sub>	V
Operating Temperature	T <sub>opr</sub>	<b>−40~85</b>	°C
Input Rise and Fall Time	t <sub>r</sub> , t <sub>f</sub>	$0 \sim 1000 (V_{CC} = 2.0V)$ $0 \sim 500 (V_{CC} = 4.5V)$ $0 \sim 400 (V_{CC} = 6.0V)$	ns

### DC ELECTRICAL CHARACTERISTICS

PARAMETER SYN		L TEST CONDITION		V <sub>cc</sub>	Ta = 25°C			Ta = −40~85°C		UNIT
PARAIVIETER	STIVIBOL	SYMBOL TEST CONDITION		(V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
High - Level Input Voltage	V <sub>IH</sub>			2.0 4.5 6.0	1.50 3.15 4.20			1.50 3.15 4.20	_ _ _	<
Low - Level Input Voltage	VIL			2.0 4.5 6.0			0.50 1.35 1.80		0.50 1.35 1.80	>
Low - Level Output Voltage	V <sub>OL</sub>	V <sub>IN</sub> =	$I_{OL} = 20 \mu A$	2.0 4.5 6.0	_ _ _	0.0 0.0 0.0	0.1 0.1 0.1		0.1 0.1 0.1	V
	V <sub>IH</sub> Or V <sub>I</sub>	V <sub>IH</sub> or V <sub>IL</sub>	$I_{OL} = 4 \text{ mA}$ $I_{OL} = 5.2 \text{ mA}$	4.5 6.0	-	0.17 0.18	0.26 0.26	_	0.33 0.33	
Output Off - State Current	l <sub>oz</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC}$		6.0	-	_	±0.5	_	± 5.0	
Input Leakage Current	I <sub>I N</sub>	$V_{IN} = V_{CC}$ or GND		6.0	_	_	± 0.1	_	± 1.0	$\mu A$
Quiescent Supply Current	$I_{CC}$	$V_{IN} = V_{CC}$ or GND		6.0	_	_	1.0	_	10.0	

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AC ELECTRICAL CHARACTERISTICS ( $C_L = 15pF$ ,  $V_{CC} = 5V$ ,  $Ta = 25^{\circ}C$ , Input  $t_r = t_f = 6ns$ )

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Transition Time	t <sub>THL</sub>		_	4	8	
Propagation Delay Time	t <sub>pLZ</sub>	$R_L = 1k\Omega$	_	5	12	ns
Propagation Delay Time	t <sub>pZL</sub>	$R_L = 1k\Omega$	_	5	12	

AC ELECTRICAL CHARACTERISTICS ( $C_L = 50pF$ , Input  $t_r = t_f = 6ns$ )

PARAMETER	SYMBOL	TEST CONDITION		Ta = 25°C		2	Ta = -40~85°C		UNIT
			V <sub>CC</sub> (V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
			2.0	_	30	75	_	95	
Output Transition Time	t <sub>THL</sub>		4.5	_	8	15	_	19	
·			6.0	_	7	13	_	16	
			2.0	_	20	75	_	95	
Propagation Delay Time	t <sub>pLZ</sub>	$R_L = 1k\Omega$	4.5	_	10	15	_	19	ns
· · · · · · · · · · · · · · · · · · ·	F		6.0	_	9	13	_	16	
Propagation Delay Time			2.0	_	24	75	_	95	
	$t_{pZL}$	$R_L = 1k\Omega$	4.5	_	8	15	_	19	
	,		6.0	_	7	13	_	16	
Input Capacitance	C <sub>IN</sub>			_	5	10	_	10	
Output Capacitance	C <sub>OUT</sub>			_	3	_	_	_	pF
Power Dissipation Capacitance	C <sub>PD</sub> (1)			_	5	_	_	_	

Note (1) C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

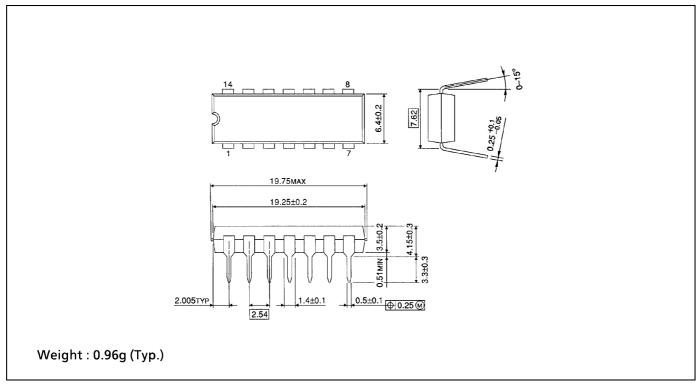
Average operating current can be obtained by the equation:

 $I_{CC}$  (opr) =  $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 4$  (per Gate)

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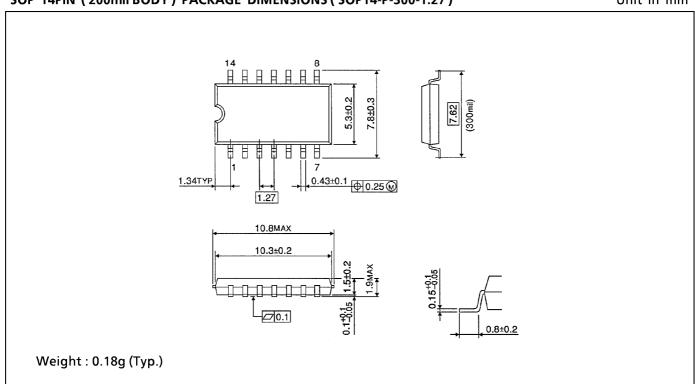
## DIP 14PIN PACKAGE DIMENSIONS (DIP14-P-300-2.54)

Unit in mm



## SOP 14PIN (200mil BODY) PACKAGE DIMENSIONS (SOP14-P-300-1.27)

Unit in mm

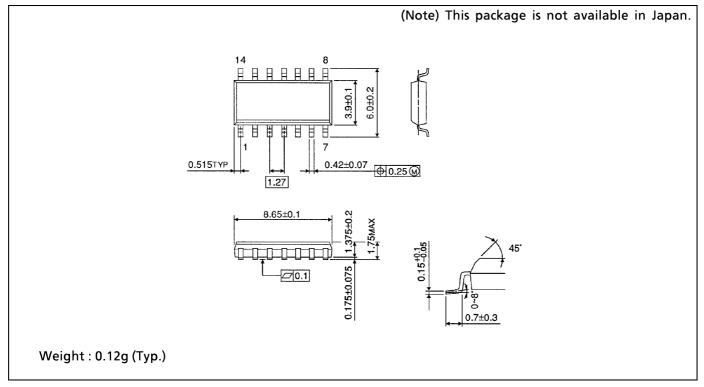


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# SOP 14PIN (150mil BODY) PACKAGE DIMENSIONS (SOL14-P-150 -1.27)

Unit in mm



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